

<b>Notice of References Cited</b>	Application/Control No. 10/674,365	Applicant(s)/Patent Under Reexamination FRENKEL ET AL.	
	Examiner Toan M. Le	Art Unit 2863	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,502,036	12-2002	Zhang et al.	702/7
X	B	US-6,643,589	11-2003	Zhang et al.	702/7
X	C	US-6,308,136	10-2001	Tabarovsky et al.	702/7
X	D	US-6,381,542	04-2002	Zhang et al.	702/7
X	E	US-6,810,331	10-2004	Bittar et al.	702/7
X	F	US-6,044,325	03-2000	Chakravarthy et al.	702/7
X	G	US-5,883,515	03-1999	Strack et al.	324/339
X	H	US-6,832,159	12-2004	Smits et al.	702/11
X	I	US-6,618,676	09-2003	Kriegshauser et al.	702/7
X	J	US-5,862,513	01-1999	Mezzatesta et al.	702/9
X	K	US-6,760,666	07-2004	Hagiwara, Teruhiko	702/7
X	L	US-6,636,045	10-2003	Tabarovsky et al.	324/343
X	M	US-6,574,562	06-2003	Tabarovsky et al.	702/7

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Mezzatesta et al., Simultaneous Inversion of Galvanic and Induction Logging Measurements to Improve Resolution, April 27-29, 1994, SPE 2679, XP-002269245, III Latin American/Caribbean Petroleum Engineering Conference, Buenos Aires, Argentina
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.